

GENERAL DESCRIPTION

The ME4812 is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density , DMOS trench technology integrated Schottky diode. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other battery powered circuits where high-side switching , and low in-line power loss are needed in a very small outline surface mount package.

FEATURES

- Integrated Schottky diode
- $R_{DS(ON)} \leq 13m\Omega @ V_{GS}=10V$
- $R_{DS(ON)} \leq 21.5m\Omega @ V_{GS}=4.5V$
- Super high density cell design for extremely low $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability

APPLICATIONS

- Power Management in Note book
- Battery Powered System
- DC/DC Converter low side switching
- Load Switch

PIN CONFIGURATION



Ordering Information: ME4812 (Pb-free)

ME4812-G (Green product- Halogen free)

Absolute Maximum Ratings ($T_A=25^\circ C$ Unless Otherwise Noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DSS}	30	V
Gate-Source Voltage	V_{GSS}	± 20	V
Continuous Drain Current ($T_J = 150^\circ C$)*	I_D	11.3	A
$T_A = 70^\circ C$		8.9	
Pulsed Drain Current	I_{DM}	45	A
Maximum Power Dissipation* ($T_A = 25^\circ C$)	P_D	2.5	W
$T_A = 70^\circ C$		1.6	
Operating Junction Temperature	T_J	-55 to 150	°C
Thermal Resistance-Junction to Ambient*	$R_{\theta JA}$	50	°C/W

* The device mounted on 1in² FR4 board with 2 oz copper

N-Channel 30-V(D-S) MOSFET, ESD Protection

Electrical Characteristics ($T_A = 25^\circ C$ Unless Otherwise Specified)

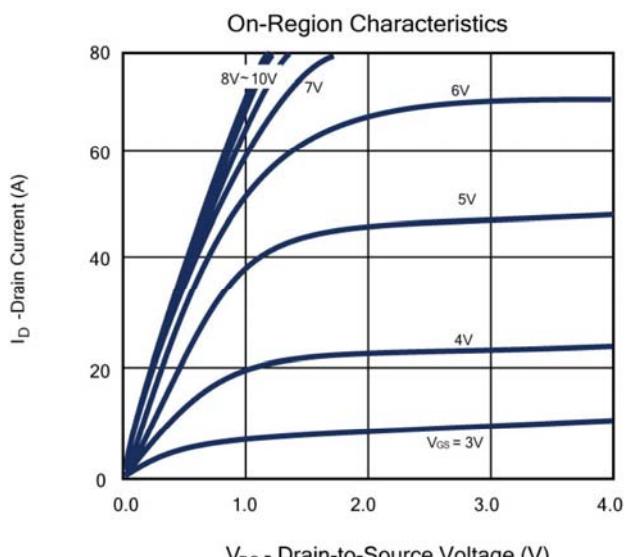
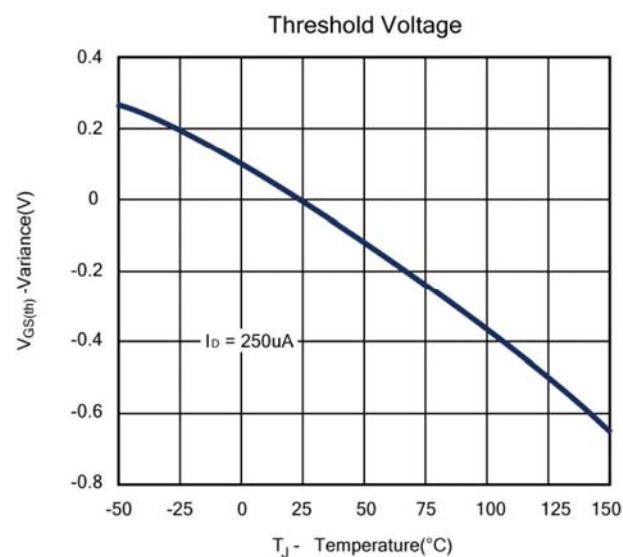
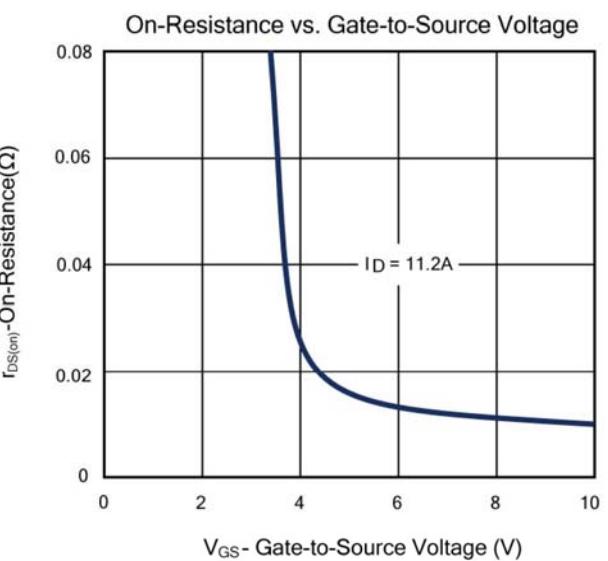
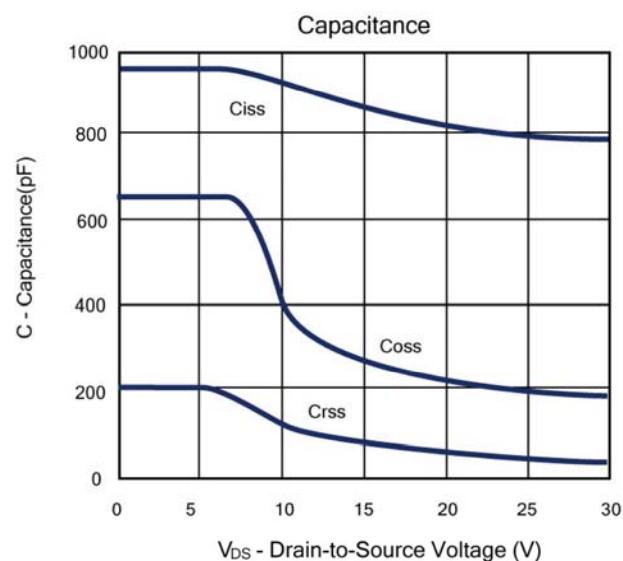
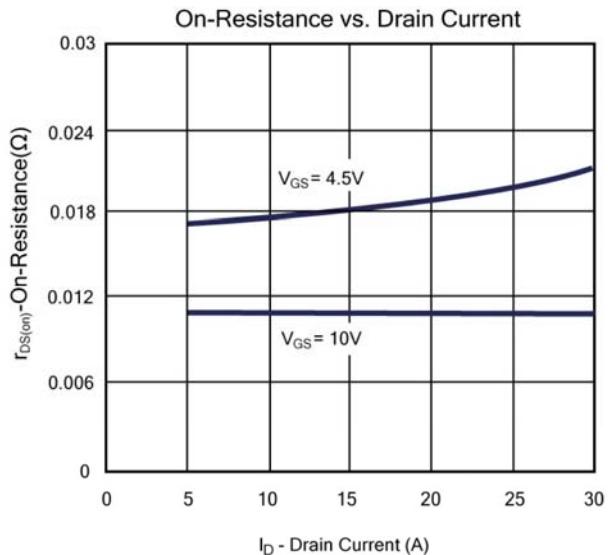
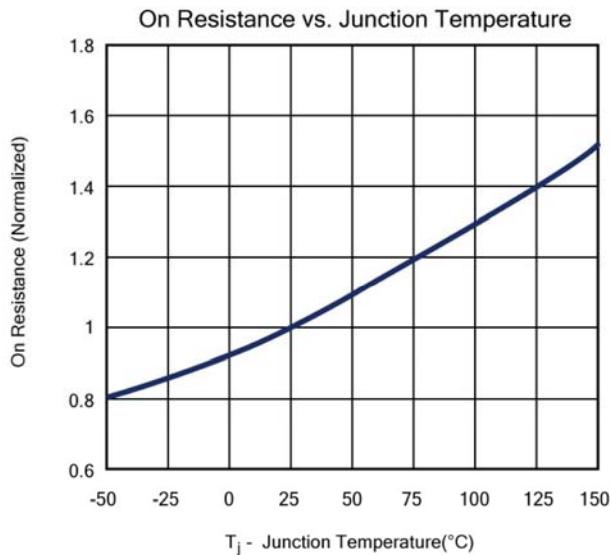
Symbol	Parameter	Limit	Min	Typ	Max	Unit
STATIC						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250 \mu A$	30			V
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250 \mu A$	1		3	V
I_{GSS}	Gate Leakage Current	$V_{DS}=0V, V_{GS}=\pm 16V$			± 10	μA
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=30V, V_{GS}=0V$			1	mA
$R_{DS(ON)}$	Drain-Source On-State Resistance ^a	$V_{GS}=10V, I_D= 11.2A$		10	13	$m\Omega$
		$V_{GS}=4.5V, I_D= 10A$		17.5	21.5	
V_{SD}	Diode Forward Voltage	$I_S=1A, V_{GS}=0V$		0.4	0.5	V
DYNAMIC						
Q_g	Total Gate Charge(10V)	$V_{DS}=15V, V_{GS}=10V, I_D=11.2A$		19		nC
Q_g	Total Gate Charge(4.5V)	$V_{DS}=15V, V_{GS}=4.5V, I_D=11.2A$		9.7		
Q_{gs}	Gate-Source Charge			4.2		
Q_{gd}	Gate-Drain Charge			4.6		
C_{iss}	Input capacitance	$V_{DS}=15V, V_{GS}=0V, f=1.0MHz$		830		pF
C_{oss}	Output Capacitance			280		
C_{rss}	Reverse Transfer Capacitance			84		
R_g	Gate-Resistance	$V_{DS}=0V, V_{GS}=0V, f=1MHz$		1		Ω
$t_{d(on)}$	Turn-On Delay Time	$V_{DD}=15V, R_L = 15\Omega$ $I_D=1A, V_{GEN}=10V$ $R_G=3\Omega$		14		ns
t_r	Turn-On Rise Time			14		
$t_{d(off)}$	Turn-Off Delay Time			39		
t_f	Turn-Off Fall Time			4		

Notes: a. Pulse test: pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$, Guaranteed by design, not subject to production testing.

b. Matsuki reserves the right to improve product design, functions and reliability without notice.

N-Channel 30-V(D-S) MOSFET, ESD Protection

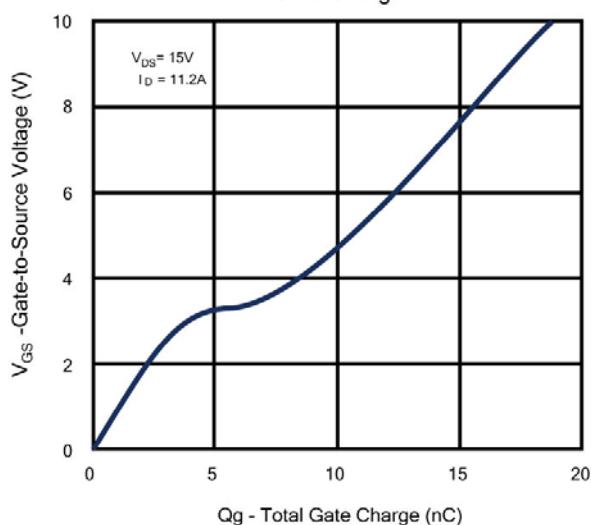
Typical Characteristics ($T_J = 25^\circ\text{C}$ Noted)



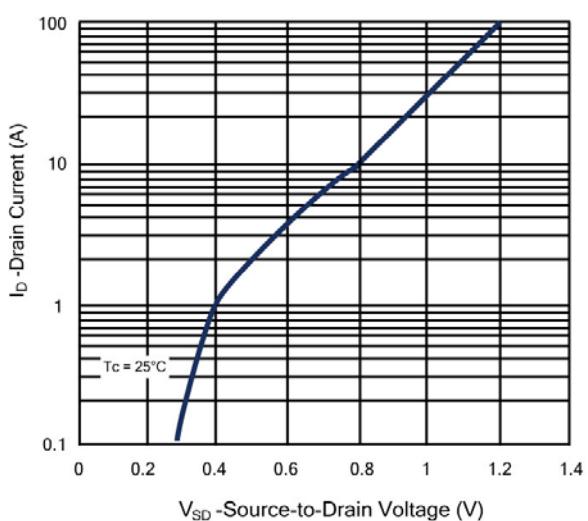
N-Channel 30-V(D-S) MOSFET, ESD Protection

Typical Characteristics (T_J = 25°C Noted)

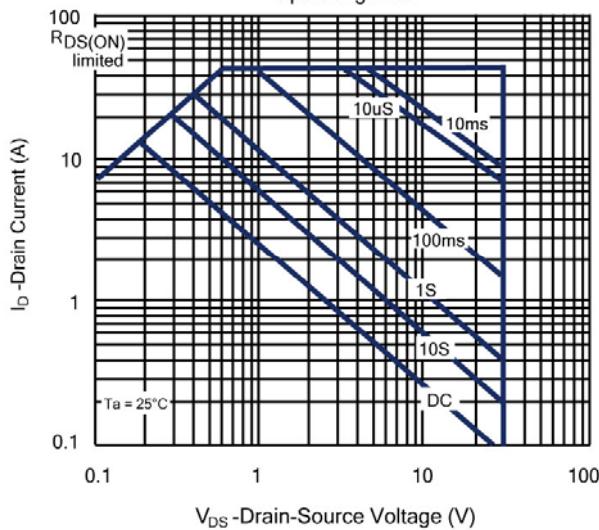
Gate Charge



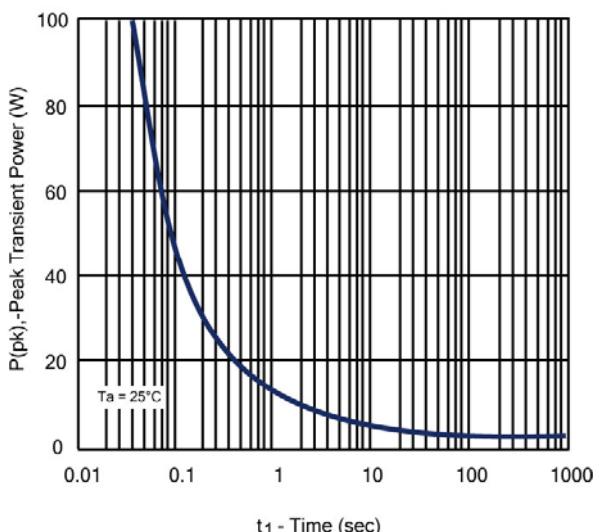
On-Resistance vs. Drain Current



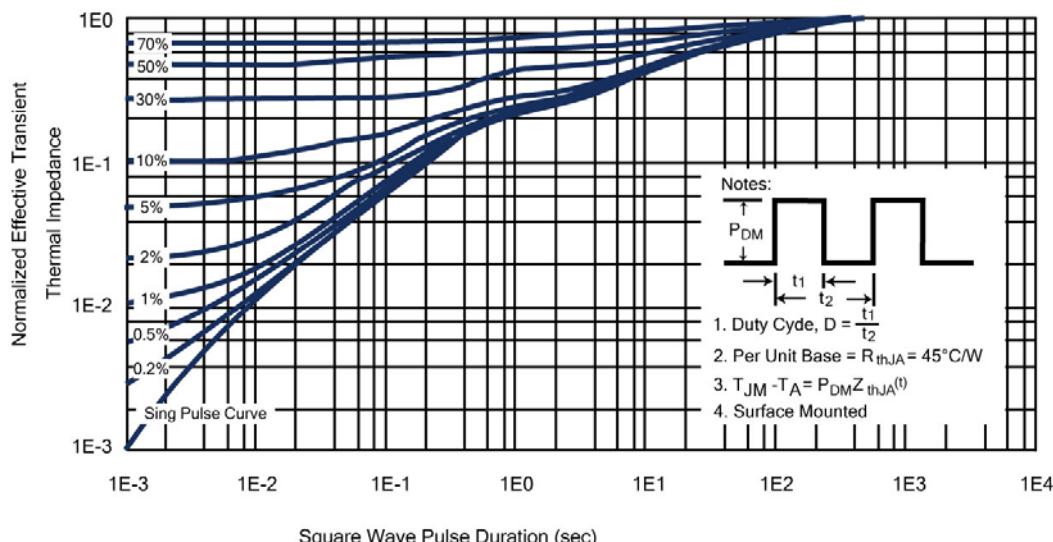
Maximum Forward Biased Safe Operating Area



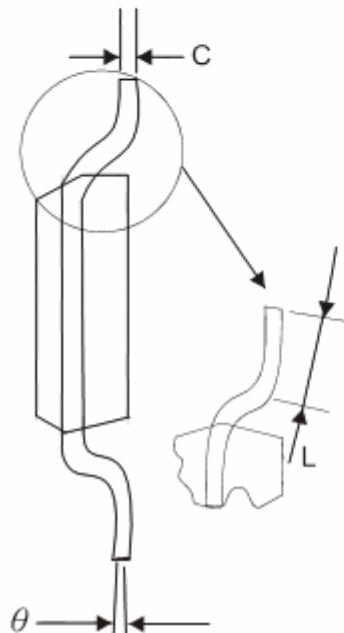
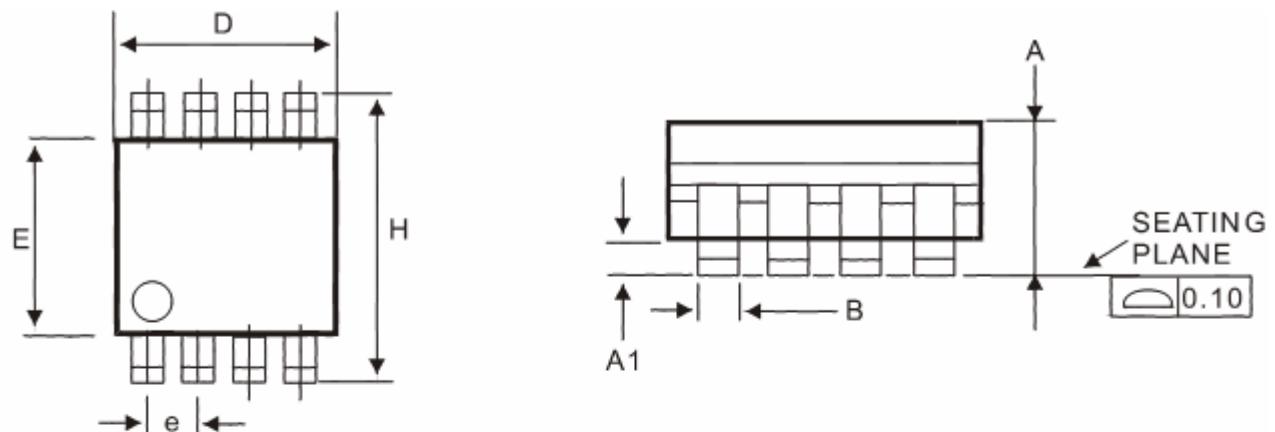
Single Pulse Maximum Power Dissipation



Normalized Thermal Transient Impedance, Junction-to-Ambient



SOP-8 Package Outline



DIM	MILLIMETERS (mm)	
	MIN	MAX
A	1.35	1.75
A1	0.10	0.25
B	0.35	0.49
C	0.18	0.25
D	4.80	5.00
E	3.80	4.00
e	1.27 BSC	
H	5.80	6.20
L	0.40	1.25
theta	0°	7°

Note: 1. Refer to JEDEC MS-012AA.

2. Dimension "D" does not include mold flash, protrusions or gate burrs . Mold flash, protrusions or gate burrs shall not exceed 0.15 mm per side.

